

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/801,706	PAN, WUN-FANG
	<b>Examiner</b> Evan Dzierzynski	<b>Art Unit</b> 2875

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner